

<b>Notice of References Cited</b>	Application/Control No. 10/797,298	Applicant(s)/Patent Under Reexamination ELKOVITCH, MARK D.	
	Examiner Jaison P. Thomas	Art Unit 1751	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,184,280	02-2001	Shibuta, Daisuke	524/405
*	B	US-6,811,724	11-2004	Majumdar et al.	252/500
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Applied Nanotech Inc. webpage ( <a href="http://www.applied-nanotech.com/cntproperties.htm">http://www.applied-nanotech.com/cntproperties.htm</a> )
	V	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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